

## Supporting Information

### Boron Nitride as a novel support for highly stable Palladium nanocatalysts by Atomic Layer Deposition

Matthieu Weber,<sup>1</sup> Cassandre Lamboux,<sup>1</sup> Bruno Navarra,<sup>1</sup> Philippe Miele,<sup>1,2</sup> Sandrine Zanna,<sup>3</sup> Maxime Dufond,<sup>4</sup> Lionel Santinacci,<sup>4</sup> Mikhael Bechelany<sup>1,\*</sup>

<sup>1</sup> Institut Européen des membranes, IEM, UMR-5635, Univ Montpellier, CNRS, ENSCM, Montpellier, France.

<sup>2</sup> Institut Universitaire de France, 1 rue Descartes, 75231 Paris, France.

<sup>3</sup> PSL Research University, Chimie ParisTech - CNRS, Institut de Recherche de Chimie Paris, 75005, Paris, France.

<sup>4</sup> Aix Marseille Univ, CNRS, CINAM, Marseille, France.

\* Correspondence: [mikhael.bechelany@umontpellier.fr](mailto:mikhael.bechelany@umontpellier.fr)

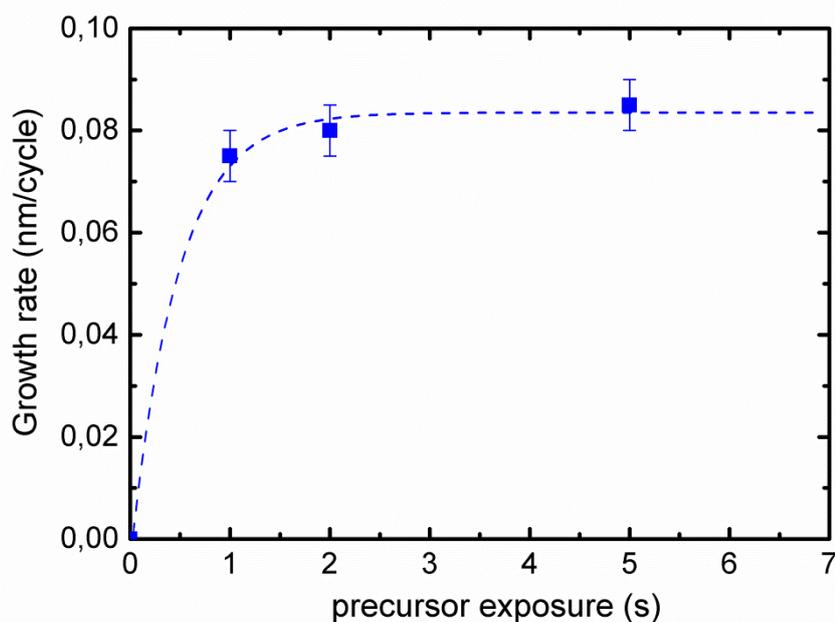
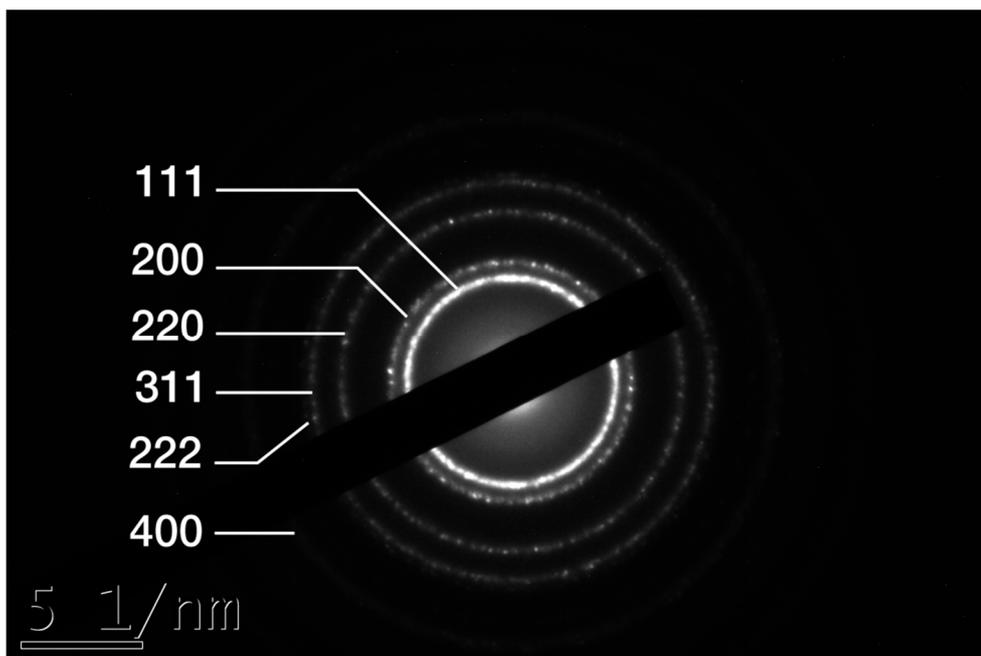


Figure S1: Saturation curve of the BN film growth as a function of the  $\text{BBr}_3$  exposure time, depicting the saturated growth of the film.

**Table S1:** Properties of BN films prepared by ALD using  $\text{BBr}_3$  as precursor and  $\text{NH}_3$  as co-reactant at  $750^\circ\text{C}$ . The substrates were Si(100) wafers and the substrate temperature was  $750^\circ\text{C}$ . In situ spectroscopic ellipsometry (SE), X-Ray reflectometry (XRR), atomic force microscopy (AFM), X-Ray photoelectron spectroscopy (XPS) measurements were used for the analysis. The films were 25 nm thick for all analysis.

<b>Properties</b>	<b>Value</b>	<b>Analysis technique</b>
Growth-per-cycle ( $\text{\AA}/\text{cycle}$ )	$0.8 \pm 0.1$	SE
Mass density ( $\text{g}/\text{cm}^3$ )	$2.2 \pm 0.3$	XRR
RMS roughness (nm)	$3.5 \pm 2$	AFM
C content (at.%)	$4 \pm 3$	XPS
O content (at.%)	$7 \pm 3$	XPS



<i>Crystal</i>	<i>Diameter of the diffraction rings (nm<sup>-1</sup>)</i>	<i>d (Å)</i>	<i>Crystal planes</i>
<i>Pd</i>	<i>8.46</i>	<i>2.36</i>	<i>111</i>
	<i>9.90</i>	<i>2.02</i>	<i>200</i>
	<i>13.93</i>	<i>1.44</i>	<i>220</i>
	<i>16.34</i>	<i>1.22</i>	<i>311</i>
	<i>17.21</i>	<i>1.16</i>	<i>222</i>
	<i>21.86</i>	<i>0.91</i>	<i>400</i>

**Figure S2:** Selected area electron diffraction of a BN/Pd NPs sample prepared using 300 cycles of the Pd ALD process, corresponding to Figure 1c. The substrates used were Si<sub>3</sub>N<sub>4</sub> TEM windows covered with 15 nm of BN. The table corresponds to the indexing of the diffraction rings.